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(12) **United States Design Patent**
Wang

(10) **Patent No.: US D921,502 S**
(45) **Date of Patent: ** Jun. 8, 2021**

(54) **TEMPERATURE PROBE**

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(**) Term: **15 Years**

(21) Appl. No.: **29/715,840**

(22) Filed: **Dec. 5, 2019**

(30) **Foreign Application Priority Data**

Jun. 6, 2019 (CN) 201930291990.2

(51) **LOC (13) Cl.** **10-04**
(52) **U.S. Cl.**
USPC **D10/58**
(58) **Field of Classification Search**
USPC D10/52, 53, 57, 58, 60
CPC . G01K 1/024; G01K 1/08; G01K 1/14; B65D 85/38
See application file for complete search history.

(56) **References Cited**

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Primary Examiner — Leanne Was-Englehart

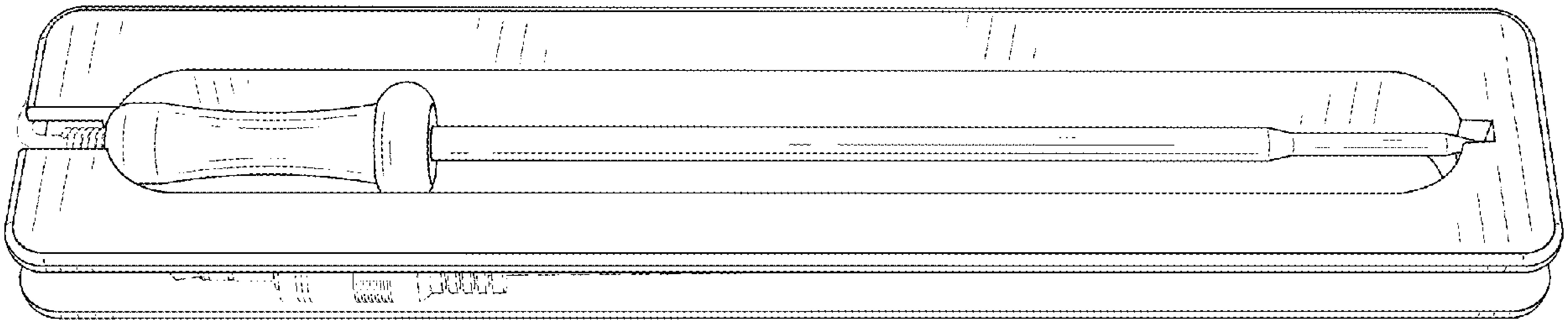
(57) **CLAIM**

The ornamental design for a temperature probe, as shown and described.

DESCRIPTION

FIG. **1** is a perspective view of a temperature probe showing my new design;
FIG. **2** is a front elevational view thereof;
FIG. **3** is a rear elevational view thereof;
FIG. **4** is a left side elevational view thereof;
FIG. **5** is a right side elevational view thereof;
FIG. **6** is a top plan view thereof; and,
FIG. **7** is a bottom plan view thereof.
The broken lines in the drawings depict portions of the temperature probe that form no part of the claimed design.

1 Claim, 7 Drawing Sheets



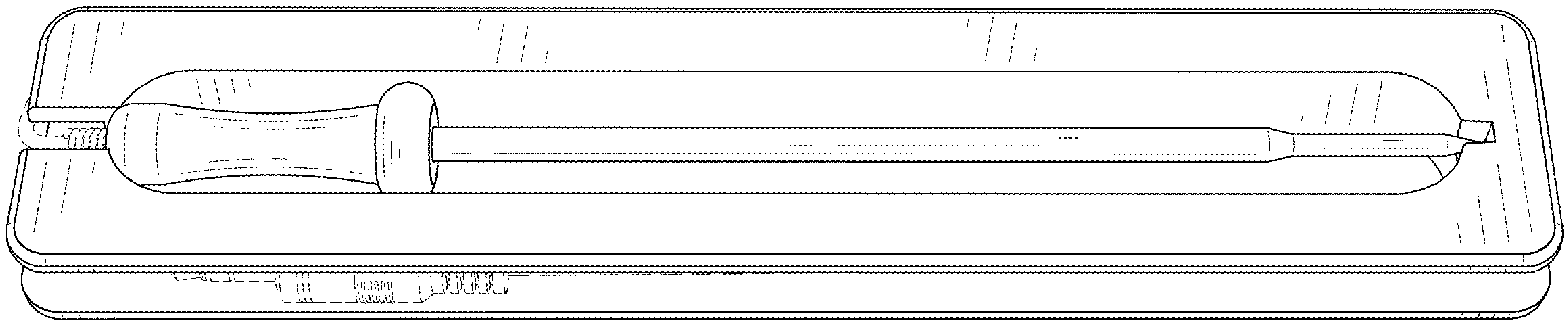


FIG. 1

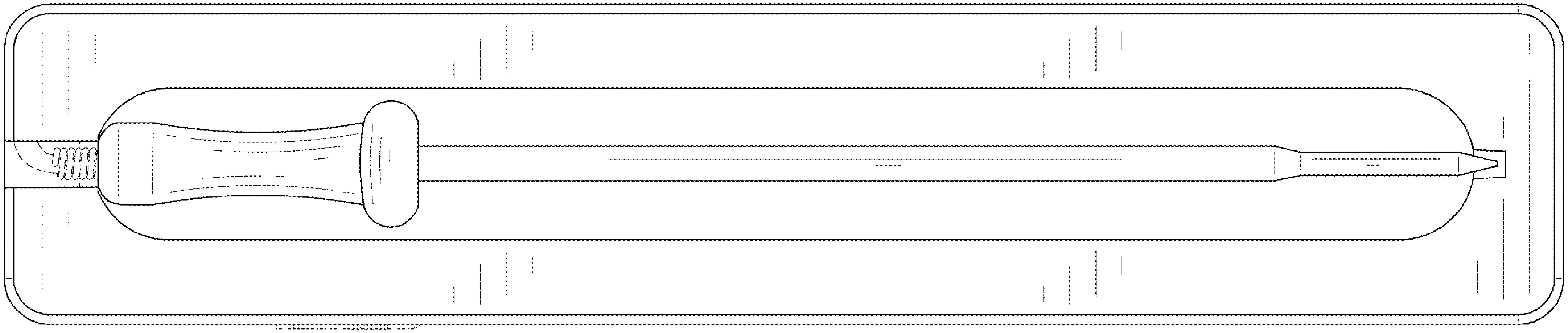


FIG. 2

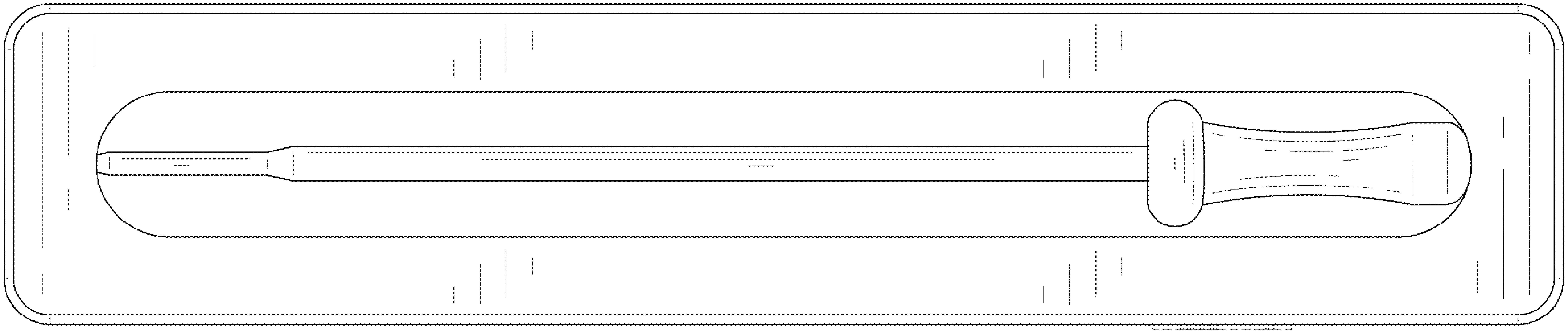


FIG. 3

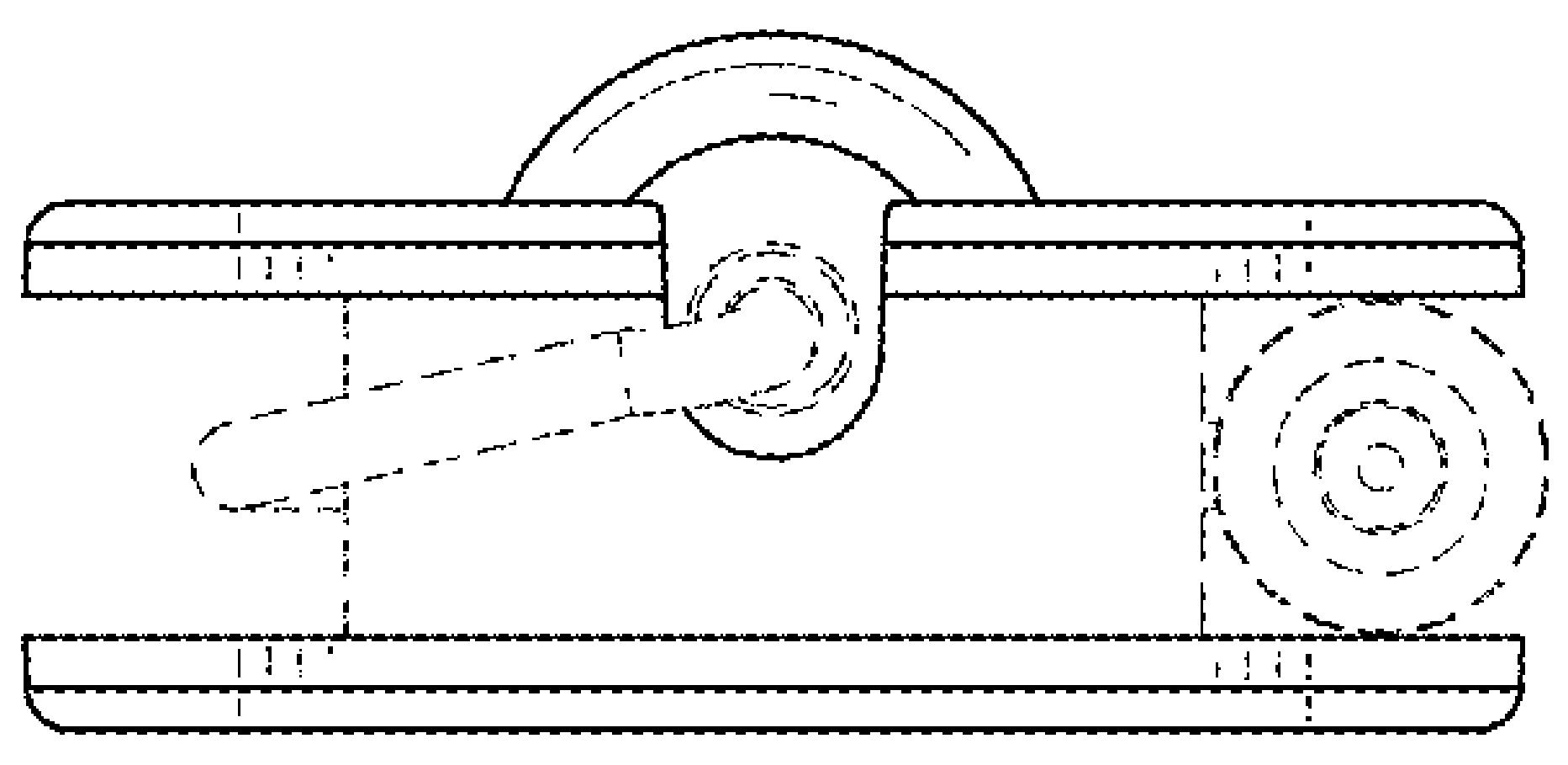


FIG. 4

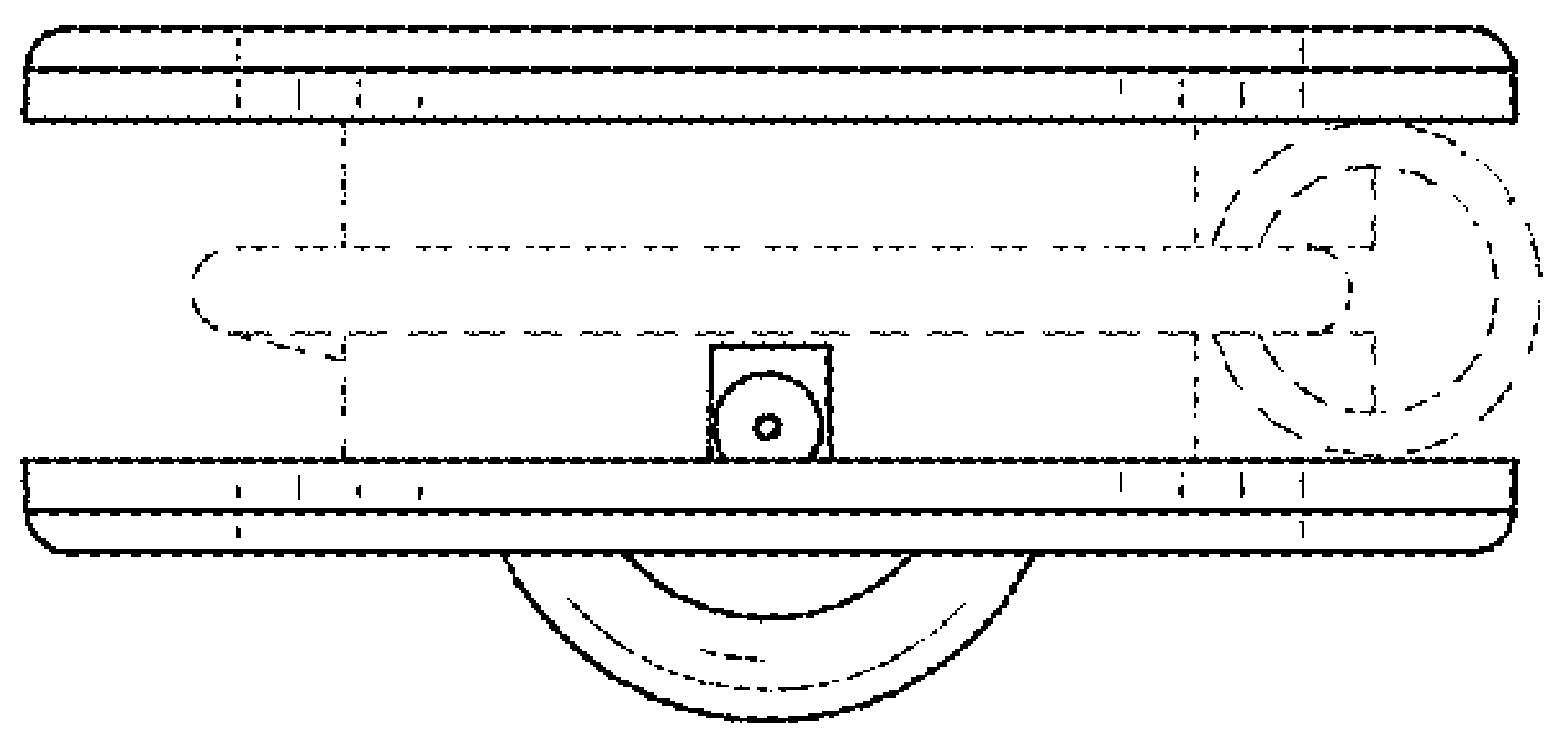


FIG. 5

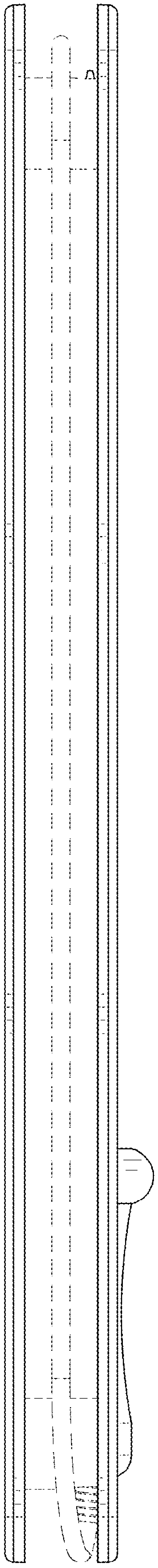


FIG. 6

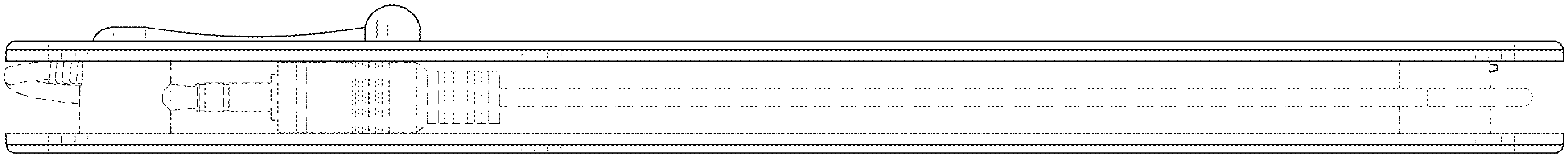


FIG. 7